

Supplementary Information for Nature of long-lived moiré interlayer excitons in electrically tunable MoS₂/MoSe₂ heterobilayers

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Table 1: **Devices parameters.** Summary of key parameters for the devices investigated in this study: twist angle (θ), fast and slow time constant for iX PL decay (τ_1 and τ_2), effective iX g-factor (g), optically-induced valley polarization in the absence of magnetic field and at saturation (ρ_{PL}^0 and $\rho_{\text{PL}}^{\text{sat.}}$), and saturation magnetic field for ρ_{PL} ($B_{\text{sat.}}$).

Device #	$\theta, ^\circ$	$\tau_1, \mu\text{s}$	$\tau_2, \mu\text{s}$	g	ρ_{PL}^0	$\rho_{\text{PL}}^{\text{sat.}}$	$B_{\text{sat.}}, T$
1	4	0.03	0.13	+6.0	-0.07	-0.13	3
2	1	1.0	4.4	+6.7	-0.04	-0.11	1.25
3	3	0.14	0.56	+2.5	-0.01	-0.07	0.02
4	1	0.33	2.2	+2.7	-0.03	-0.10	≤ 0.25
5	3	0.3	1.7	+1.0	-0.01	-0.09	≤ 1
6	1	0.8	3.0	+8.0	0.0	-0.06	0.2
7	28	n.a.	n.a.	n.a.	n.a.	n.a.	n.a.
8	27	n.a.	n.a.	n.a.	n.a.	n.a.	n.a.

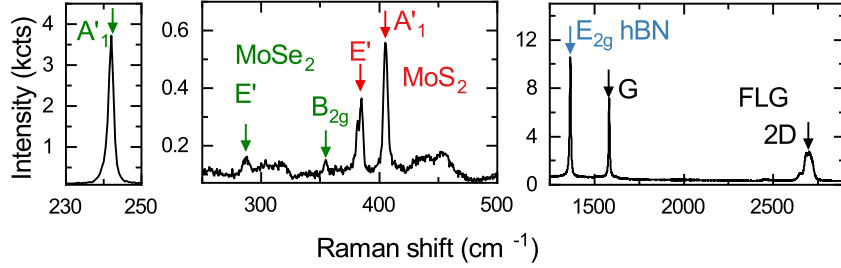


Figure S1: **Raman spectroscopy.** Raman spectra from the device, acquired at room temperature using 2.33 eV optical excitation. Dominant peaks in the 50-500 cm^{-1} range correspond to in-plane A'_1 mode at 241.9 (405.4) cm^{-1} and out-of-plane E' mode at 286.7 (384.0) cm^{-1} of MoSe₂ (MoS₂).¹ The peak at 354.7 cm^{-1} is out-of-plane B_{2g} mode of MoSe₂, which is Raman inactive on monolayers,² but becomes active in few-layers and heterobilayers due to the reduction of symmetry elements.³ Higher-frequency range shows E_{2g} mode at from hBN encapsulation layers at 1365 cm^{-1} ⁴ and the G and $2D$ Raman modes from FLG gates, at 1582 and ~ 2697 cm^{-1} ,⁵ respectively.

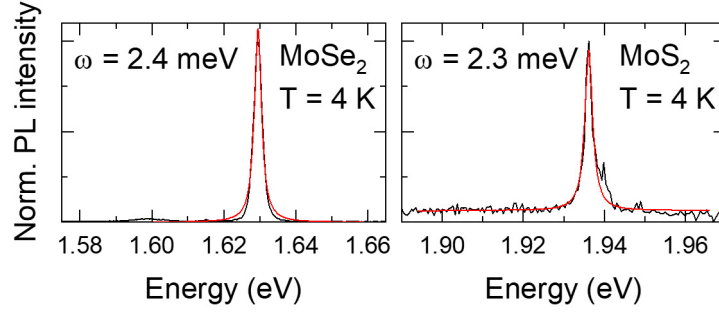


Figure S2: **Photoluminescence spectroscopy of constituent monolayers.** PL spectra recorded in (left) MoSe₂ and (right) MoS₂ monolayer regions at 4 K. The neutral exciton peak linewidth approaches the homogeneous limit, confirming the high optical quality.

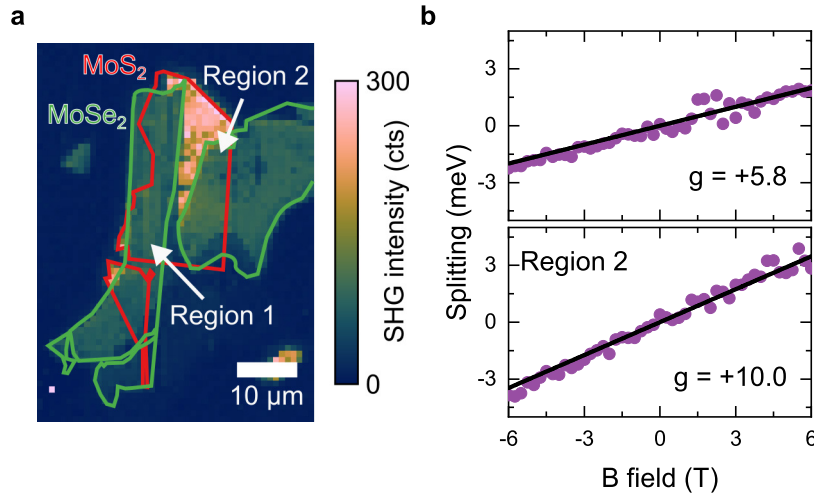


Figure S3: **Stacking configuration identification.** (a) Map of SHG intensity recorded in Device 6 at room temperature using 1320 nm excitation, containing heterobilayer Regions 1 and 2 with the opposite stacking created using tear-and-stack method. Both regions demonstrate similar SHG intensity, preventing reliable identification of stacking configuration. (b) Energy splitting between $\sigma+$ and $\sigma-$ polarized PL as a function of out-of-plane magnetic field for heterobilayer Regions 1 and 2.

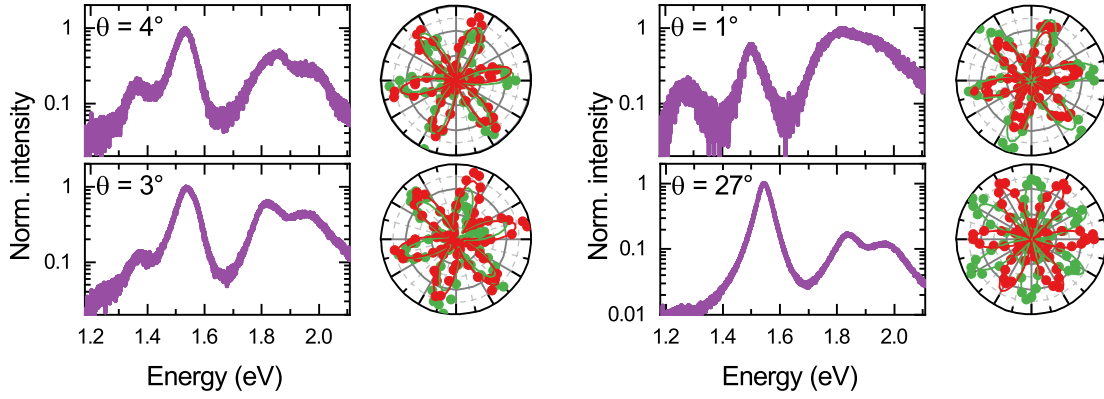


Figure S4: **Twist angle effects.** Normalized PL spectra and polar plots of polarization-resolved SHG signals acquired at room temperature in four devices with different rotational alignment between the TMD layers. Three devices with close rotational alignment ($\theta \leq 5^\circ$) show iX peak in the PL spectrum, which is not present in the PL spectrum of the strongly misaligned device ($\theta \approx 27^\circ$).

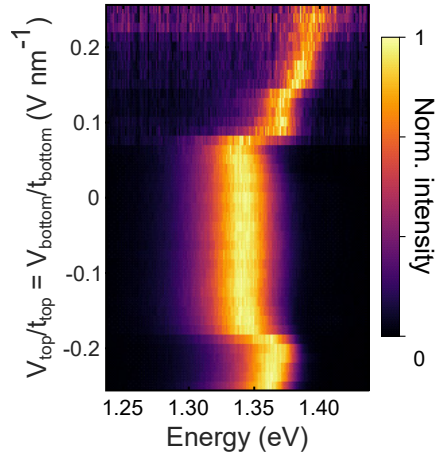


Figure S5: **Doping dependence of iX emission.** Normalized PL spectrum as a function of electrostatic doping of the TMD heterostructure, with $V_{\text{top}}/t_{\text{top}} = V_{\text{bottom}}/t_{\text{bottom}}$. Here, V_{top} (V_{bottom}) is the gate bias applied between the top (bottom) graphene electrode and the heterostructure, and t_{top} (t_{bottom}) is the thickness of the top (bottom) hBN dielectric.

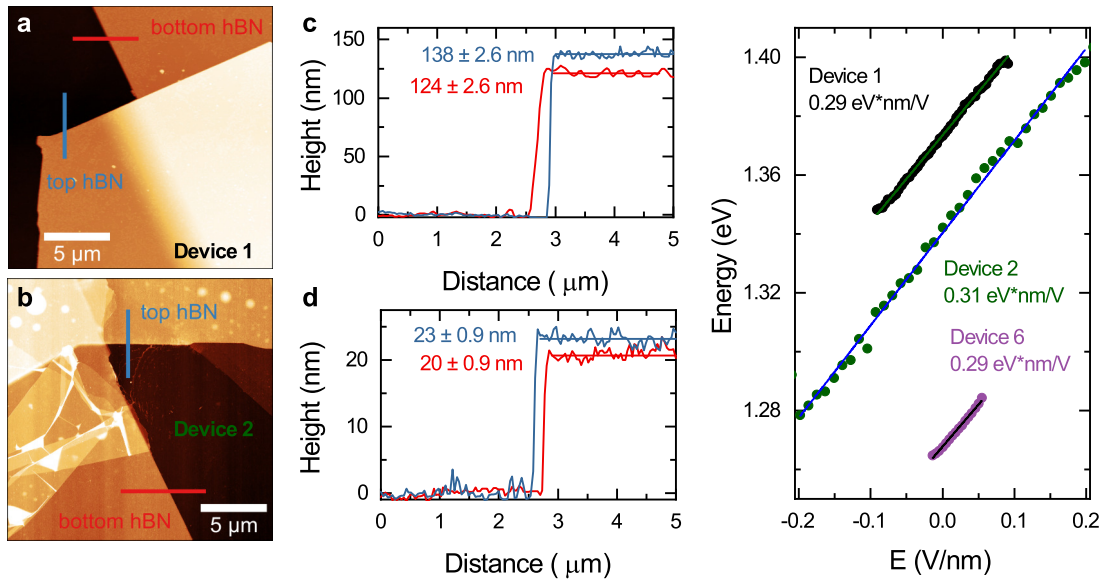


Figure S6: **Dipole size identification.** (a-c) (a and b) AFM topography images of devices 1 and 2 acquired at the edges of top and bottom hBN encapsulation layers and (c and d) cross-sections taken at the positions identified by the corresponding colour lines, showing the thickness of the layers. (e) Change of iX emission energy under applied out-of-plane electric field measured in Devices 1,2, and 6. The rate of change of ~ 0.3 eV V/nm extracted from the linear fit corresponds to the dipole size of ~ 0.55 nm.

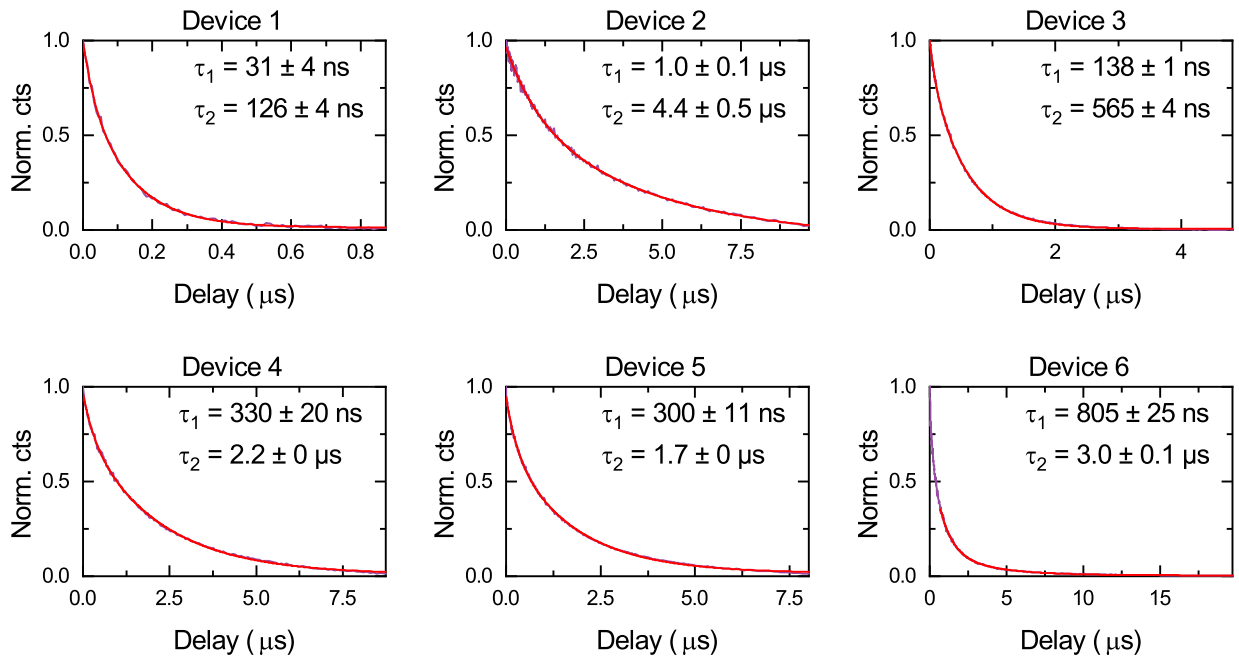


Figure S7: **iX lifetimes.** iX PL decay acquired in Devices 1-6. Solid red lines are bi-exponential fits to the data, time constants extracted from the fit are presented next to each curve.

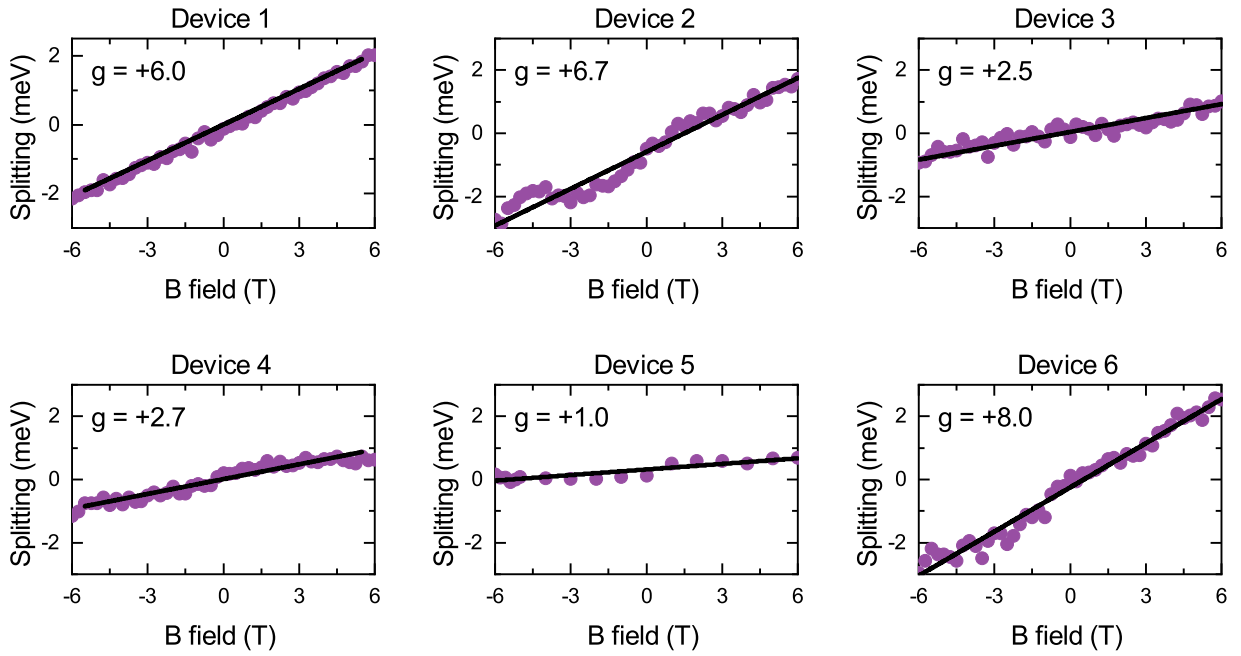


Figure S8: **iX effective g-factors.** Energy splitting between σ^+ and σ^- polarized PL as a function of out-of-plane magnetic field for Devices 1-6. Landé g factors extracted using linear fitting are listed next to each plot.

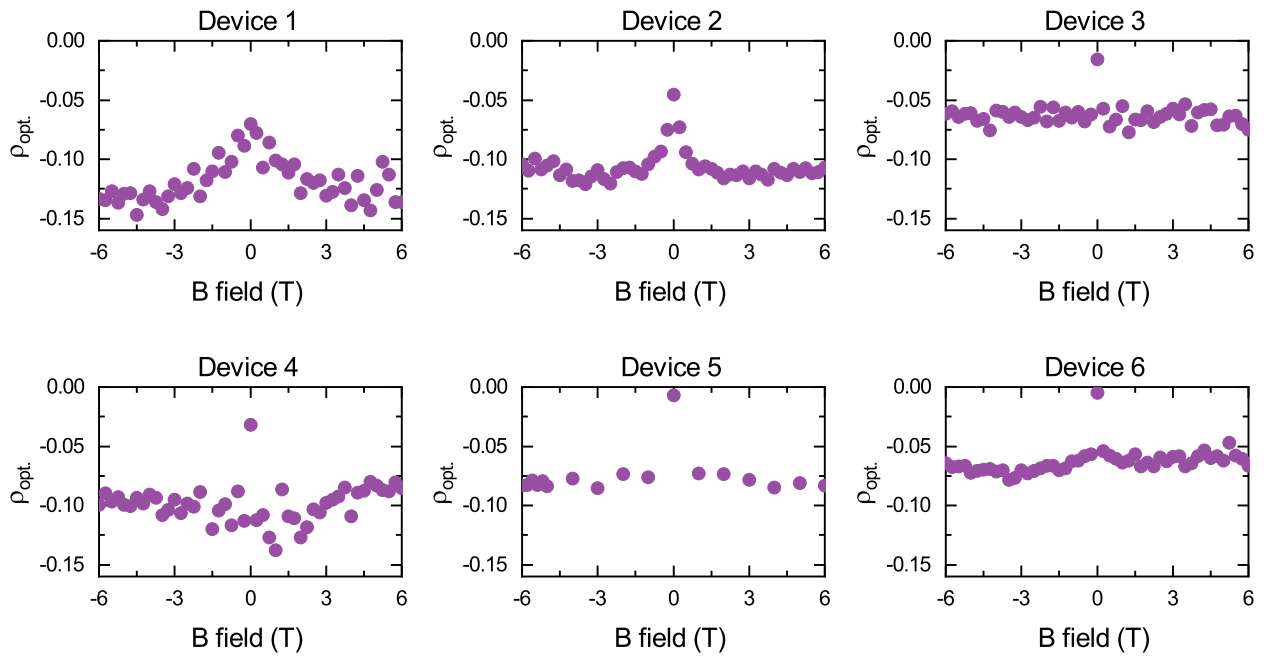


Figure S9: **Optically induced valley polarization.** Changes of optically induced iX PL valley polarization under applied magnetic field for Devices 1-6.

References

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